

**Search Notes**

Application/Control No.

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Examiner

John D. Lee

Applicant(s)/Patent under  
Reexamination

KAWANISHI ET AL.

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
359	326-332	1/11/2006	JDL
	(Updated)		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Previous USPTO "WEST" Database search updated (same search terms)	1/11/2006	JDL